

[Error Analysis and Retention-Aware Error Management for NAND Flash Memory](#)

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Publication: Intel Technology Journal

Volume / Number / Pagination: 17 / 1 / 140?164

Barcelona Supercomputing Center - Centro Nacional de Supercomputación

Source URL (retrieved on 20 jun 2021 - 05:15): <https://www.bsc.es/ca/node/40563>